# organic papers

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#### Key indicators

Single-crystal X-ray study T = 298 K Mean  $\sigma$ (C–C) = 0.004 Å R factor = 0.050 wR factor = 0.136 Data-to-parameter ratio = 14.4

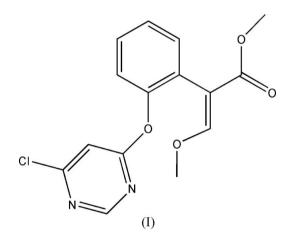
For details of how these key indicators were automatically derived from the article, see http://journals.iucr.org/e.

# (E)-Methyl 2-[2-(6-chloropyrimidin-4-yloxy)phenyl]-3-methoxyacrylate

In the molecule of the title compound,  $C_{15}H_{13}ClN_2O_4$ , the pyrimidine and benzene rings form a dihedral angle of 69.3 (3)°. No  $\pi$ - $\pi$  stacking interactions are observed in the crystal structure.

## Comment

The title compound, (I), can be used as an intermediate in the preparation of fungicides (Jones et al., 1998). We report here the crystal structure of (I)



The molecular structure of (I) is shown in Fig. 1. Bond lengths and angles are within normal ranges (Allen et al., 1987). The dihedral angle between the pyrimidine and benzene rings is 69.3 (3)°. The O2-O4/C13-C17 and C7-C12 planes are inclined at an angle of 71.0 (1)°. An intramolecular C-H...O hydrogen bond (Table 1) is observed in the molecular structure.

## **Experimental**

Compound (I) was prepared according to the literature method of Jones et al. (1998). Single crystals were obtained by dissolving compound (I) (0.5 g) in ethanol (50 ml) and evaporating the solvent slowly at room temperature for about 10 d.

Crystal data	
$C_{15}H_{13}ClN_2O_4$	Z = 4
$M_r = 320.72$	$D_x = 1.453 \text{ Mg m}^{-3}$
Monoclinic, $P2_1/n$	Mo $K\alpha$ radiation
a = 13.2642 (11)  Å	$\mu = 0.28 \text{ mm}^{-1}$
b = 7.7971 (7) Å	T = 298 (2) K
c = 14.2757 (12)  Å	Block, colourless
$\beta = 96.88 \ (3)^{\circ}$	$0.40 \times 0.30 \times 0.20 \text{ mm}$
V = 1465.8 (2) Å <sup>3</sup>	

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### Data collection

Enraf–Nonius CAD-4 diffractometer  $\omega/2\theta$  scans Absorption correction:  $\psi$  scan (North *et al.*, 1968)  $T_{\min} = 0.896, T_{\max} = 0.946$ 2861 measured reflections

#### Refinement

Refinement on  $F^2$   $R[F^2 > 2\sigma(F^2)] = 0.050$   $wR(F^2) = 0.136$  S = 1.002861 reflections 199 parameters H-atom parameters constrained 2861 independent reflections 2003 reflections with  $I > 2\sigma(I)$  $R_{int} = 0.000$  $\theta_{max} = 26.0^{\circ}$ 3 standard reflections every 200 reflections

intensity decay: none

$$\begin{split} &w = 1/[\sigma^2(F_{\rm o}{}^2) + (0.067P)^2 \\ &+ 0.5P] \\ &\text{where } P = (F_{\rm o}{}^2 + 2F_{\rm c}{}^2)/3 \\ (\Delta/\sigma)_{\rm max} = 0.001 \\ \Delta\rho_{\rm max} = 0.18 \ {\rm e}{}^{\rm A}{}^{-3} \\ \Delta\rho_{\rm min} = -0.26 \ {\rm e}{}^{\rm A}{}^{-3} \end{split}$$

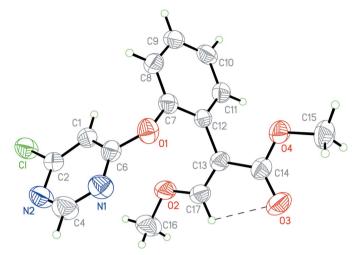
## Table 1

Hydrogen-bond geometry (Å,  $^\circ).$ 

$D - H \cdot \cdot \cdot A$	D-H	$H \cdot \cdot \cdot A$	$D \cdots A$	$D - \mathbf{H} \cdot \cdot \cdot A$
C17-H17A···O3	0.93	2.45	2.776 (3)	101

H atoms were positioned geometrically  $[C-H = 0.93 (Csp^2) \text{ or } 0.96 \text{ Å} (methyl)]$  and constrained to ride on their parent atoms, with  $U_{iso}(H) = xU_{eq}(C)$ , where x = 1.2 for  $Csp^2$  and x = 1.5 for other H atoms.

Data collection: *CAD-4 Software* (Enraf–Nonius, 1985); cell refinement: *CAD-4 Software*; data reduction: *XCAD4* (Harms & Wocadlo, 1995); program(s) used to solve structure: *SHELXS97* (Sheldrick, 1997); program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997); molecular graphics: *SHELXTL* (Bruker, 2000); software used to prepare material for publication: *SHELXTL*.



#### Figure 1

The molecular structure of (I), with the atom-numbering scheme. Displacement ellipsoids are drawn at the 50% probability level. The dashed line indicates a hydrogen bond.

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